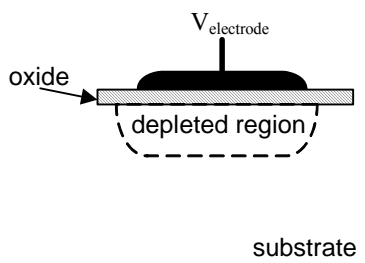
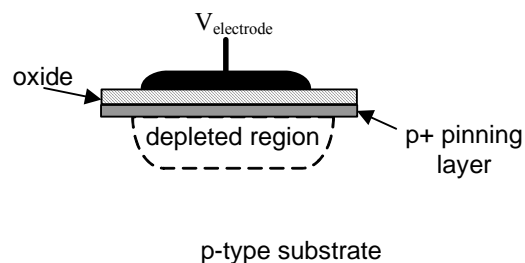


## Digital Camera Sensors

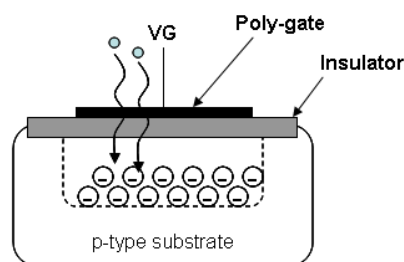
- Problem with simple photodiode is low current
- Rapidly reach the noise limits for low light
- But film integrates the photon signal
- With film can do integrations of hours of signal
- (Film though is  $\sim 1\%$  efficient in light conversion)
- Want a sensor which integrates the photodiode
- Charge Couple Devices (CCD) were the first to do that
- CCD is related to photogate detector (one cell of it)
- Create a gate over a silicon region
- Apply voltage to gate to create a depleted region
- If voltage creates the Space Charge Layer as in photodiode
- Now this traps photoelectrons



(a) Standard Photogate.



(b) Buried Photogate.



**Standard Photogate.**

## Pixel performance metrics

- Performance measured: Quantum Efficiency (QE) and responsivity
- Light comes to photodiode/photogate
- Some is reflected
- Different wavelengths have different penetration depths
- Electron hole pairs may be lost through recombination/traps

$$QE = \eta = \frac{\# \text{ Generated, Collected } \_ \text{ Electron - Hole - Pair}}{\# \text{ incident } \_ \text{ photons}}$$

- Photocollection is a function of wavelength
- Hence express as function of  $\lambda$

$$\eta = \frac{I_{ph} / e}{P_o / h\nu},$$

$I_{ph}$  is the photogenerated current

$P_o$  is the incident light power.

$h$  is planck's constant

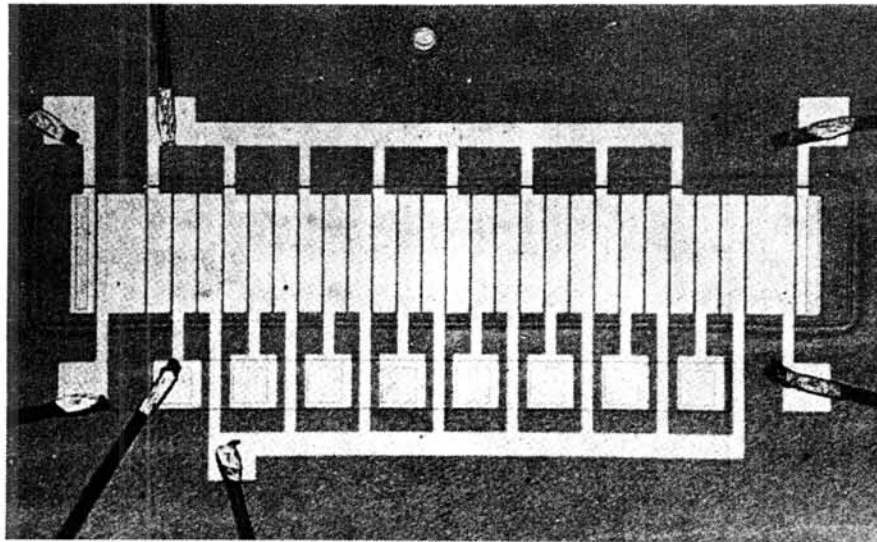
- Express responsivity in output current

$$R = \frac{I_{ph}(A)}{P_o(W)} = \eta \frac{e\lambda}{hc}.$$

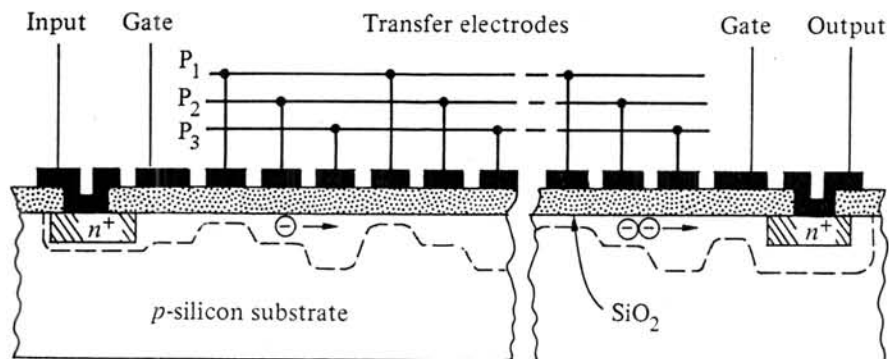
- A good photodetector QE ~90-95% over visible spectrum

## Charge Coupled Devices

- CCD's developed in 1970
- Linear array of MOS Capacitor like structures
- Originally looked at for memor storage (Bit Buckets)
- Now primary application in imaging devices



(a)

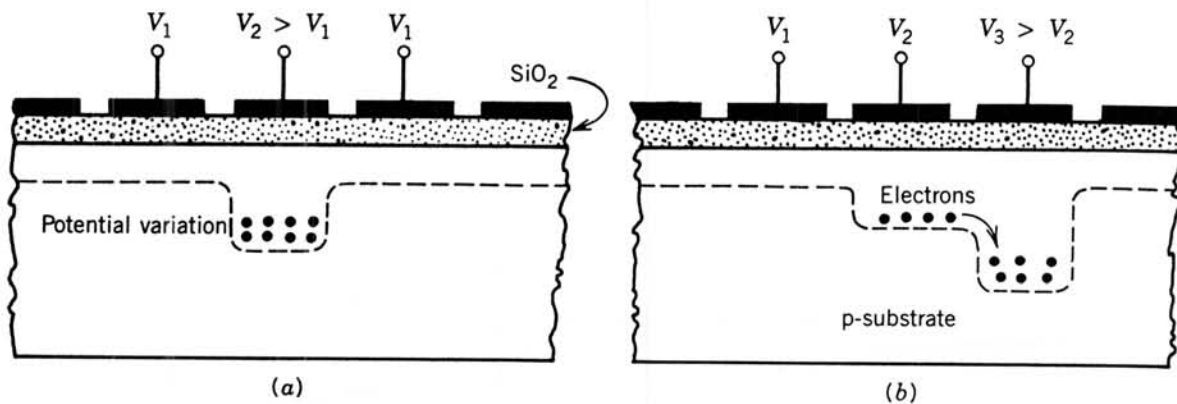


(b)

**Fig. 5** First charge-coupled device comprising eight three-phase elements and input-output gates and diodes, shown (a) in plan view and (b) schematically in its cross-sectional view. (From Tompsett et al., [9].)

## Charge Sortage and CCD

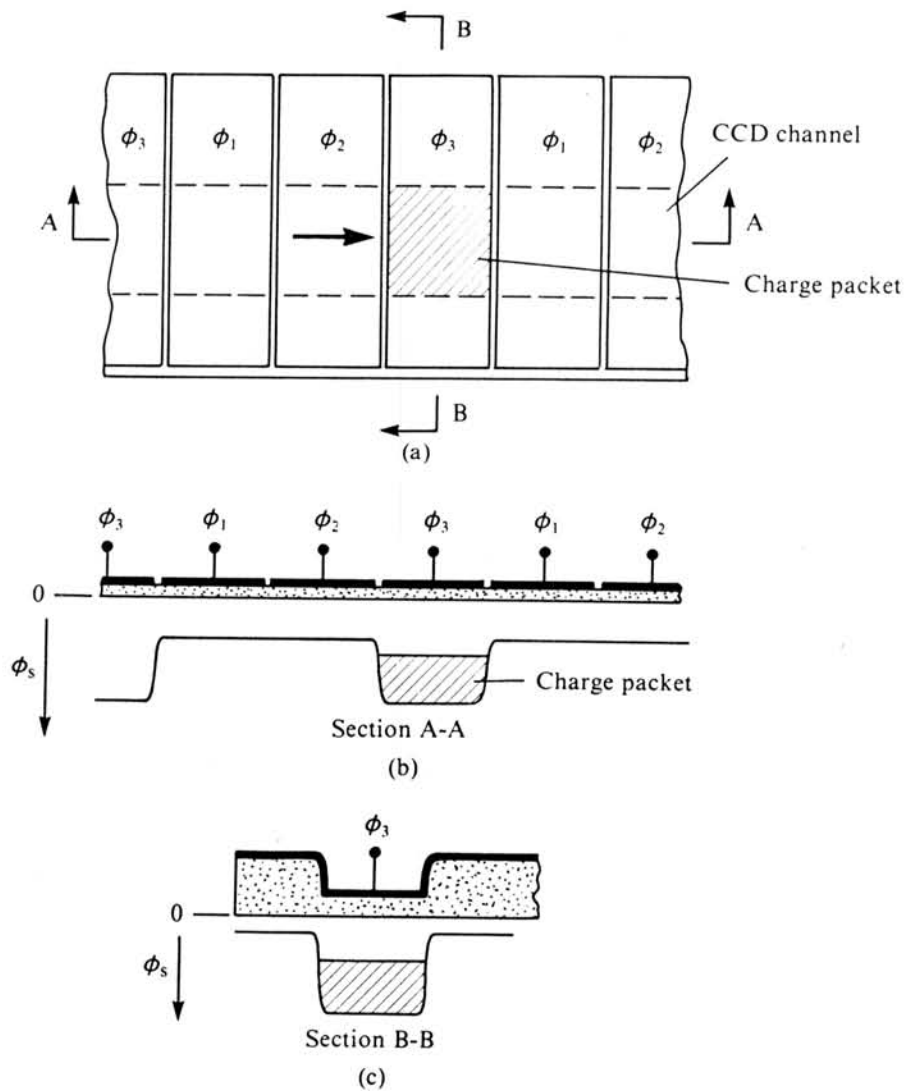
- Series of gate lines over oxide on p substrate
- let  $V_2 > V_1$  then create deep depletion well (both  $V_1$  and  $V_3$  at  $V_1$  value)
- Surface potential well under the 2nd line
- Charges from say light e-h pairs become trapped
- At time  $t_0$  increase  $V_3$  so  $> V_2$
- now well deeper for 3rd line
- Electrons flow into lower well
- Now have coupled and tranfered the charge



**FIGURE 16.26** Cutaway view of a CCD illustrating the processes of (a) charge storage and (b) charge transfer.

## Charge Trapping

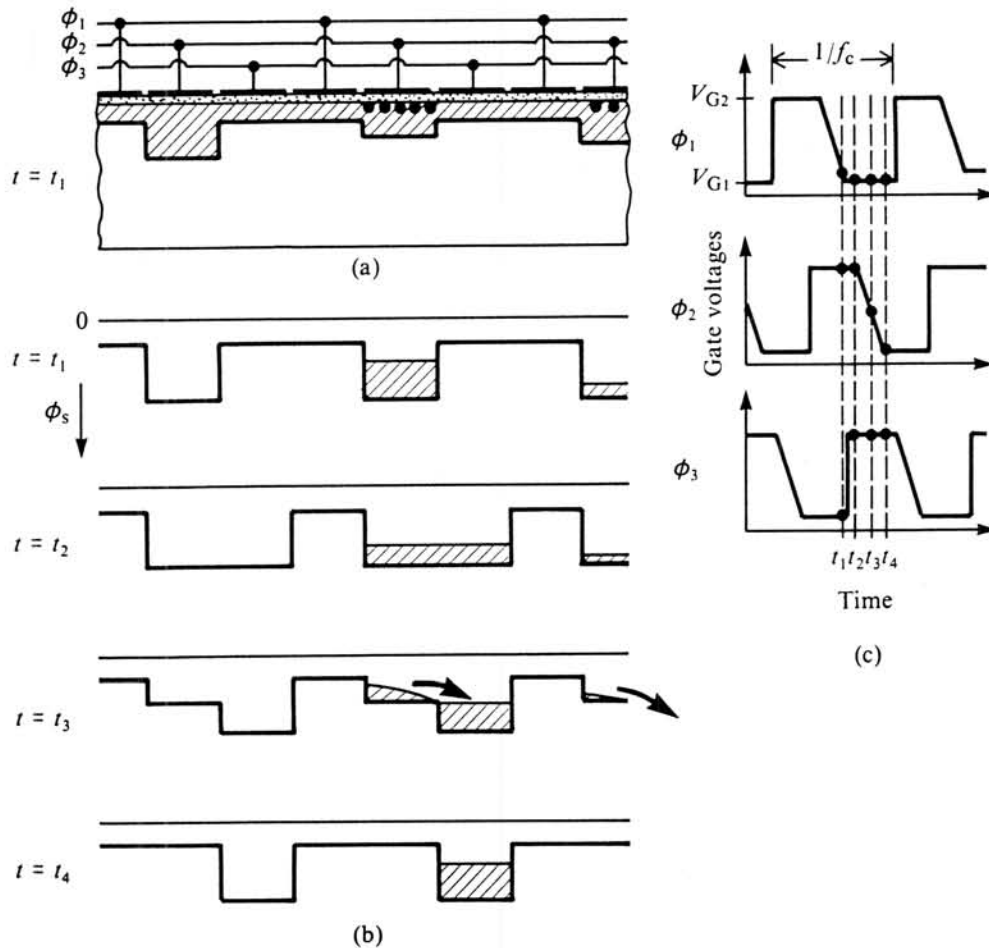
- Charge trapped in both demensions
- array of gate lines in x direction
- In y have gate oxide thickness small only in trapped region



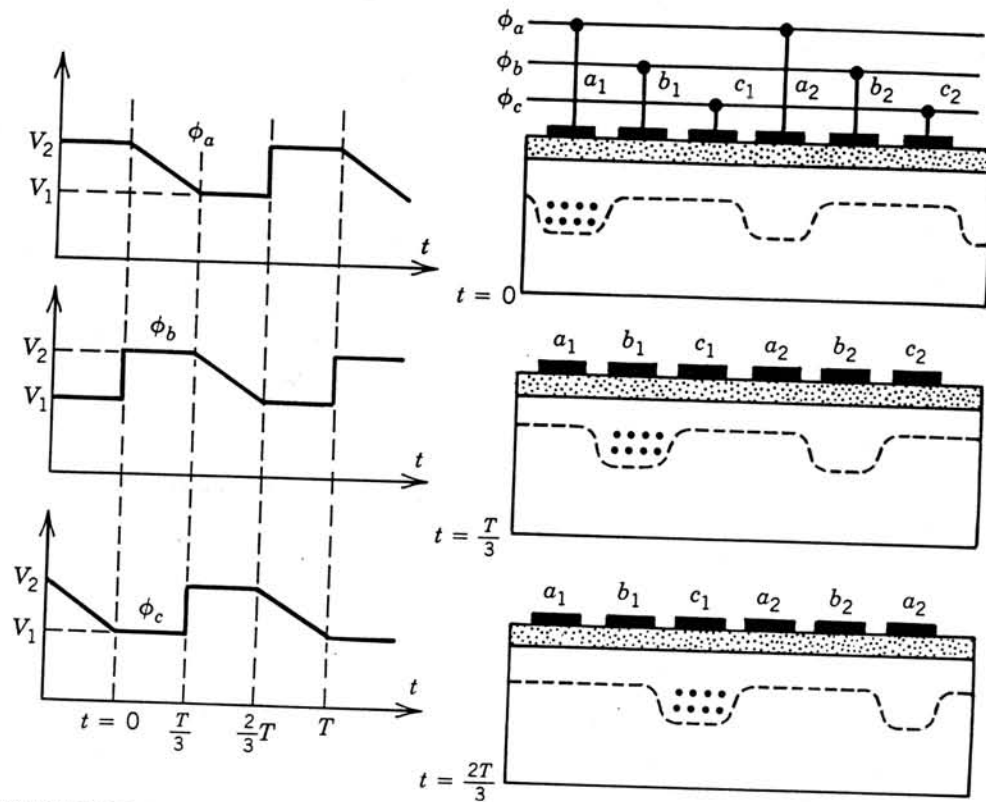
**Fig. 3.10** Charge confinement in a CCD. The charge is the shaded region in (a). It is confined along A-A by the gate potentials, with  $V_{G3} > V_{G1} = V_{G2}$ , in (b), and along B-B by the two different oxide thicknesses in (c).

## Three Phase CCD Operation

- Use a 3 phase clock in repeating 3 line sets
- Move charge to adjacent well
- Then isolate that well



**Fig. 3.11** (a) Device cross section, and (b) surface potential diagrams for times  $t_1$ ,  $t_2$ ,  $t_3$ , and  $t_4$  shown on the clock-voltage waveform diagram in (c).

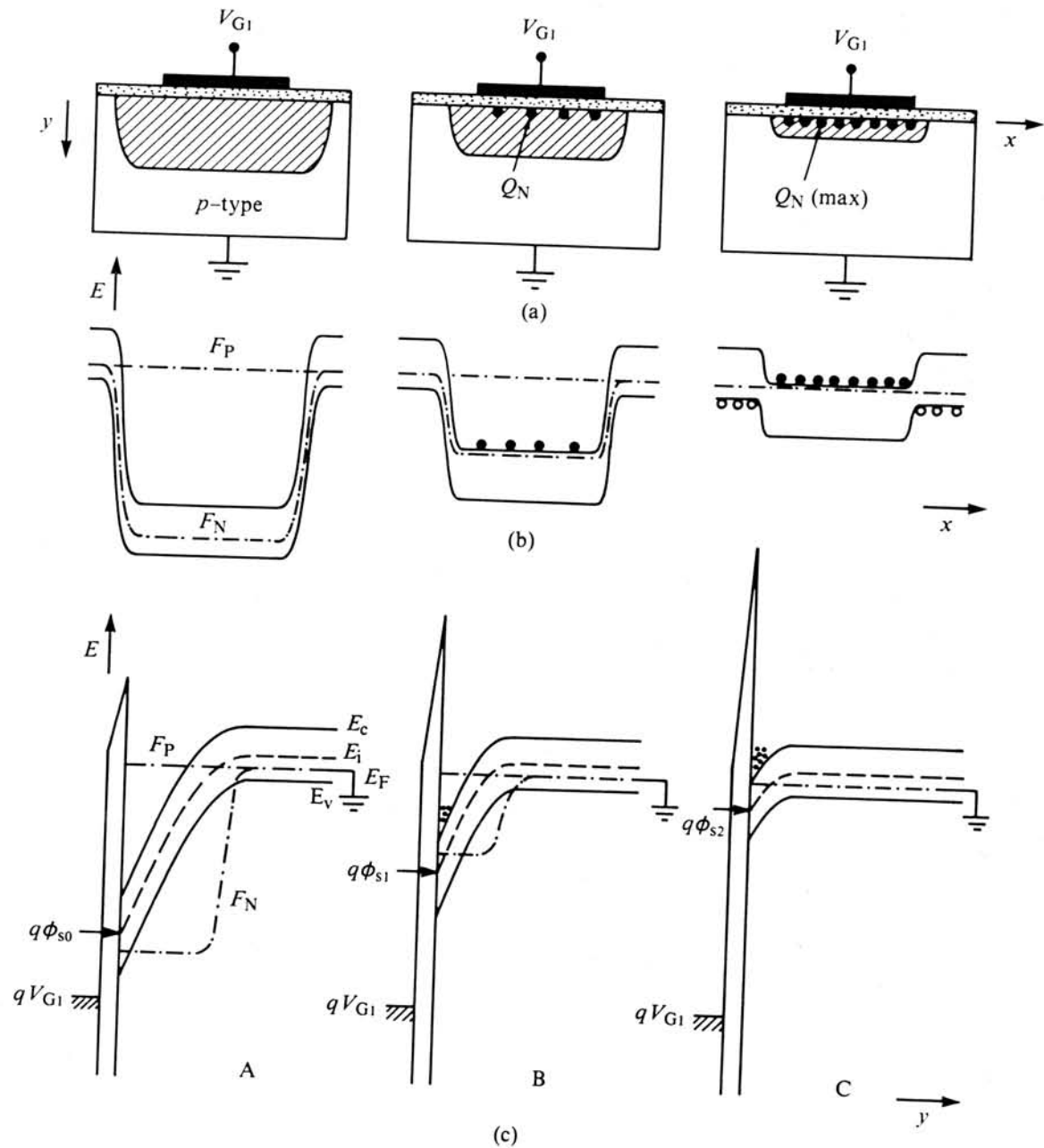


**FIGURE 16.27** Schematic diagrams illustrating the operation of a three-phase CCD. (After W. S. Boyle and G. E. Smith, Charge coupled semiconductor devices, *Bell Syst. Tech. J.*, vol. 49, p. 589. Copyright © 1970 AT&T. Reprinted by special permission.)

## CCD and Deep Depletion

- Important operation for CCD is Deep Depletion
- Recall that was when Voltage change faster than recombination could supply carriers
- Then go into deep depletion instead of inversion
- Time taken for carriers to move in Thermal Relaxation Time several seconds to many minutes depending on CCD
- Cool CCD to reduce that time (Dark Current noise)
- If charge of carriers minority carrier introduced  $Q_{sig}$  eg by e-h pairs from light
- Collects under gate and cause reduction in surface potential





**Fig. 3.6** MOS-C of Fig. 3.5 for points A, B, and C. (a) shows the space-charge regions, (b) shows the potential diagrams along  $x$  for  $y = 0$ , and (c) shows the potential diagrams along  $y$  into the semiconductor. The inversion charge is indicated by the solid circles.

## Potentials in CCD

- Recall that charges modify the surface potential
- Relation to gate bias is

$$V_G - V_{FB} = -\frac{Q_s}{C_o} + \phi_s$$

- where

$$\phi_s = \frac{qN_A W^2}{2\epsilon_s \epsilon_0}$$

- If a signal charge is present then surface charge becomes

$$Q_s = -qN_A W - Q_{sig}$$

- Thus the gate and potential relationship now becomes

$$V_G - V_{FB} = \frac{qN_A W}{C_o} + \frac{Q_{sig}}{C_o} + \phi_s$$

- Eliminating W and solving for the potential yields

$$\phi_s = V'_G + V_o - (2V'_G V_o + V_o^2)^{1/2}$$

- where

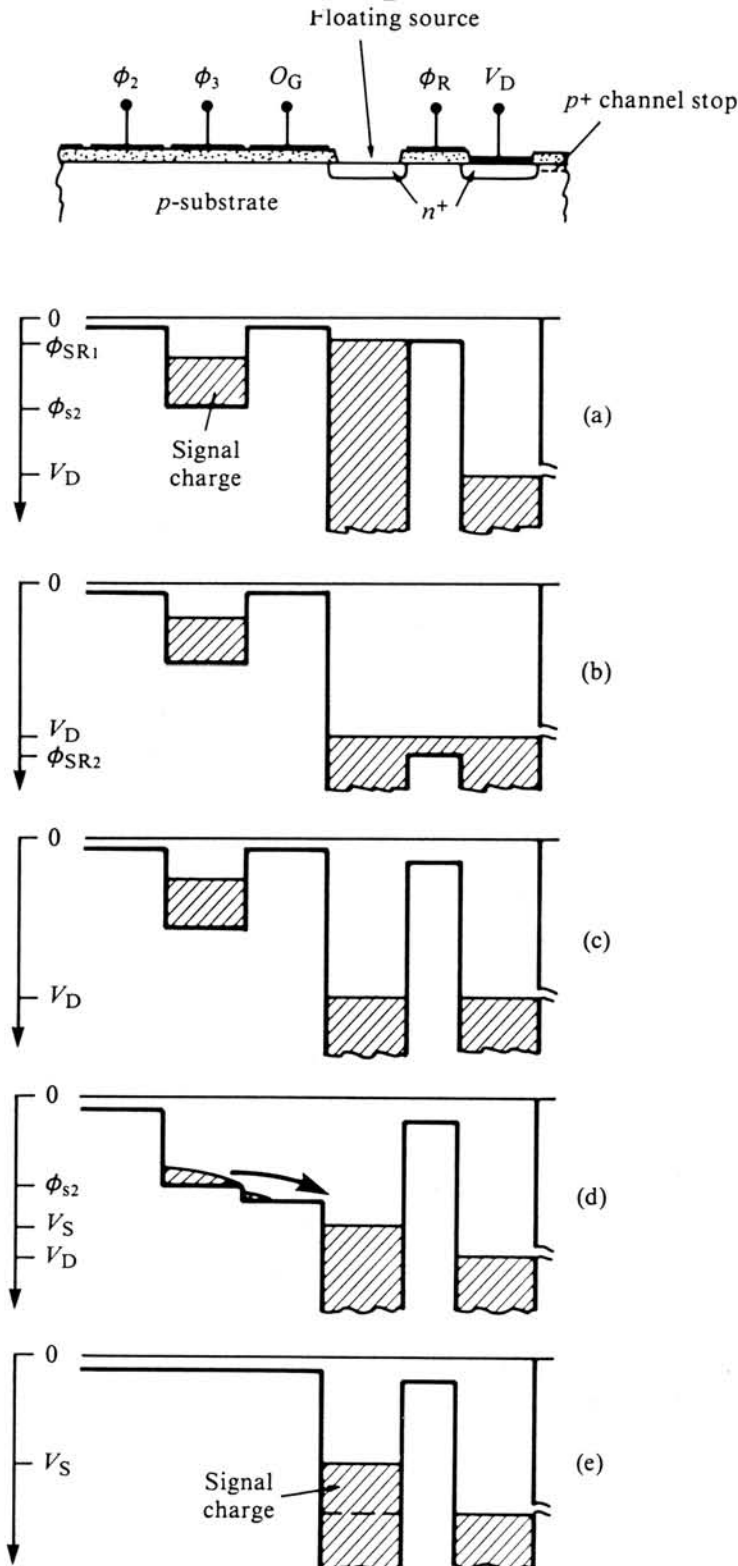
$$V'_G = V_G - V_{FB} - \frac{Q_{sig}}{C_o}$$

$$V_o = \frac{qN_A 2\epsilon_s \epsilon_0}{C_o^2}$$

- Thus surface potential decreases almost linearly with signal charge

## CCD output

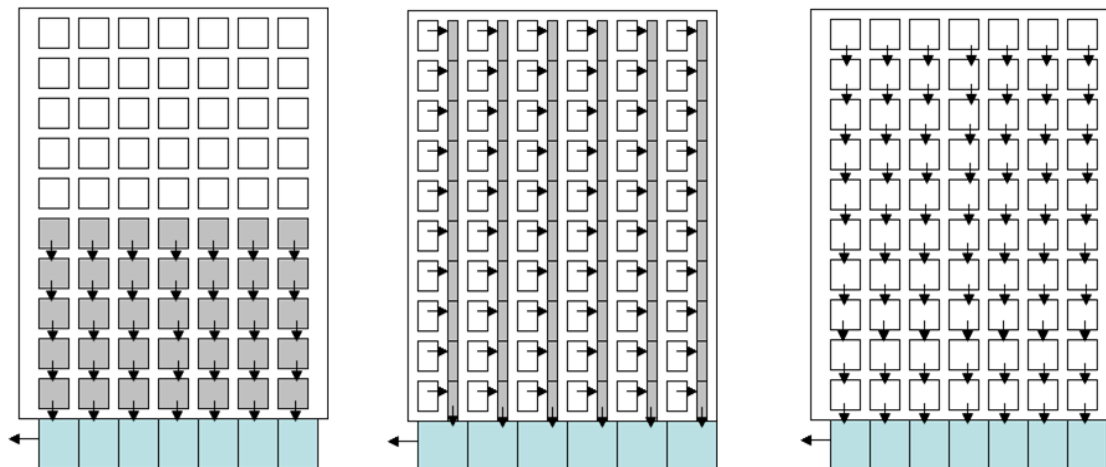
- at output goes to floating diode and a transistor source
- charges collected when gate of transistor
- Lowers potential and charge flows in
- Acts as a source follower amplifier



**Fig. 3.13** The floating diffusion output, showing the main output circuit and the potentials at various stages, as discussed in the text.

## CCD in a full Device

- CCDs were first successful digital cameras
- In the sensor array had several formats depending on output
- Imagers is an x by y array of CCDs
- Frame Transfer: move whole sensor array into another array
- Reason: fast transfer (output array is shielded from light)
- Then read out the array at needed speed
- Suffers from a smear problem
- Interline Transfer: photodiode collects e-n pairs
- Transfers to masked vertical CCD pixels
- transfer into the horizontal shift register one row at a time
- read by the output circuit
- Full-Frame CCD: most popular
- Entire array is photosensitive
- Shift data to output where it flows out
- Needs an external mechanical shutter



(a) Frame Transfer (FTCCD)    (b) Interline Transfer (ITCCD)    (c) Full Frame (FFCCD)

Common CCD structures (a) Frame Transfer, (b) Interline Transfer, (c) Full Frame.

## **Why Did CCDs go away**

- CCDs have high QE
- Still used for most sensitive scientific work
- Especially when cooled to reduce noise
- However big problem is must be powered during exposure
- Also during readout
- Hence high power consumption
- Also requires specialized fabrication process
- Most early cameras were CCDs (Kodak, Nikon)
- CMOS APS began to replace them about 2008